

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/606,138	AYYAVU ET AL.
	Examiner	Art Unit
	James K. Trujillo	2116

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Databases: EAST NPL: IEEE, ACM	12/8/2004	JKT
updated	5/9/2005	JKT
updated	9/1/2005	JKT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference search, see search history		9/1/2005	JKT